

Notice of References Cited

Application/Control No.

10/591,959

Applicant(s)/Patent Under
Reexamination
MAEDE ET AL.

Examiner

Thuy V. Tran

Art Unit

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Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,330,163 B2	02-2008	Nakai et al.	345/1.1
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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